

QIAOXIN N-Channel Enhancement Mode Power MOSFET

Description

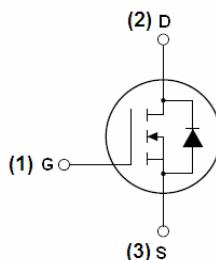
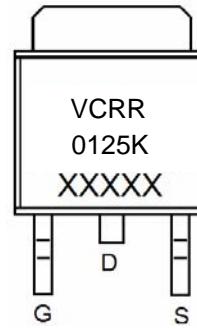
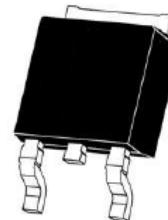
The VCRR0125K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

- $V_{DS} = 100V, I_D = 25A$
- $R_{DS(ON)} < 36m\Omega @ V_{GS}=10V$ (Typ:31 mΩ)
- Special process technology for high ESD capability
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

**Schematic diagram****Marking and pin assignment****TO-252-2L top view****Package Marking and Ordering Information**

Device Marking	Device	Device Package
VCRR0125K		TO-252-2L

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Limit	Unit
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current-Continuous	25	A
$I_D (100^\circ C)$	Drain Current-Continuous($T_c=100^\circ C$)	17.6	A
I_{DM}	Pulsed Drain Current	70	A
P_D	Maximum Power Dissipation	70	W
	Derating factor	0.5	W/ $^\circ C$
E_{AS}	Single pulse avalanche energy ^(Note 5)	110	mJ
T_J, T_{STG}	Operating Junction and Storage Temperature Range	-55 To 175	$^\circ C$

Thermal Characteristic

R _{θJC}	Thermal Resistance, Junction-to-Case ^(Note 2)	2	°C/W
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Electrical Characteristics (T_c=25°C unless otherwise noted)

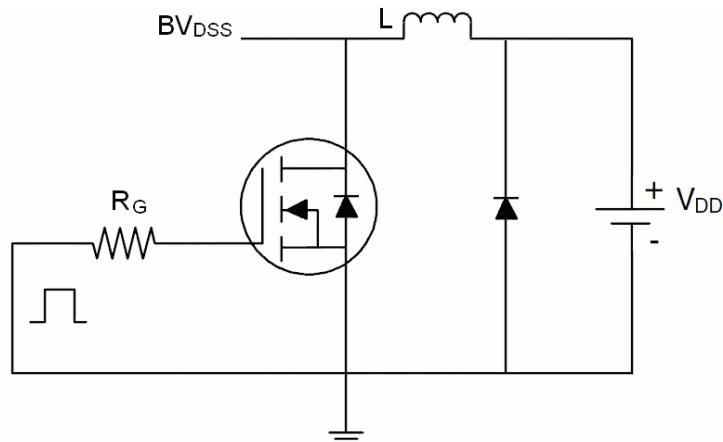
Symbol	Parameter	Condition	Min	Typ	Max	Unit
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	110	-	V
I _{DS}	Zero Gate Voltage Drain Current	V _{DS} =100V, V _{GS} =0V	-	-	1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
On Characteristics ^(Note 3)						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.0	1.6	2.2	V
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =10V, I _D =15A	-	31	36	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =15A	-	12	-	S
Dynamic Characteristics ^(Note 4)						
C _{iss}	Input Capacitance	V _{DS} =50V, V _{GS} =0V, F=1.0MHz	-	3000	-	PF
C _{oss}	Output Capacitance		-	92	-	PF
C _{rss}	Reverse Transfer Capacitance		-	18.3	-	PF
Switching Characteristics ^(Note 4)						
t _{d(on)}	Turn-on Delay Time	V _{DD} =50V, R _L =5Ω V _{GS} =10V, R _{GEN} =3Ω	-	9	-	nS
t _r	Turn-on Rise Time		-	9	-	nS
t _{d(off)}	Turn-Off Delay Time		-	31	-	nS
t _f	Turn-Off Fall Time		-	9	-	nS
Q _g	Total Gate Charge	V _{DS} =50V, I _D =25A, V _{GS} =10V	-	70.4	-	nC
Q _{gs}	Gate-Source Charge		-	9.0	-	nC
Q _{gd}	Gate-Drain Charge		-	15.3	-	nC
Drain-Source Diode Characteristics						
V _{SD}	Diode Forward Voltage ^(Note 3)	V _{GS} =0V, I _S =25A	-	-	1.2	V
I _S	Diode Forward Current ^(Note 2)	-	-	-	25	A
t _{rr}	Reverse Recovery Time	T _J = 25°C, IF = 25A di/dt = 100A/μs ^(Note 3)	-	34	-	nS
Q _{rr}	Reverse Recovery Charge		-	56	-	nC

Notes:

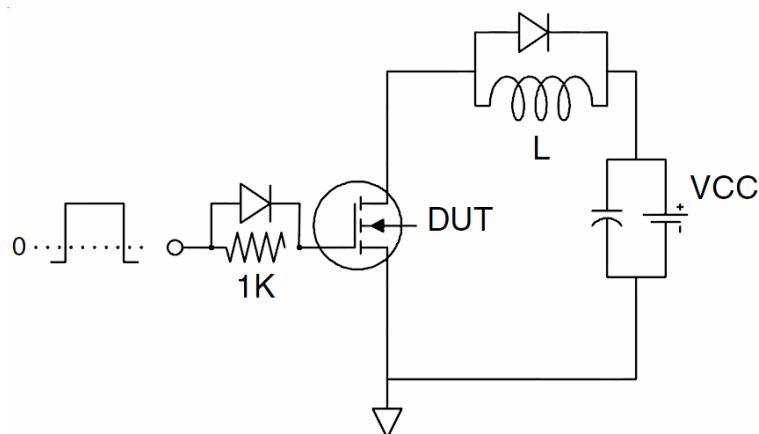
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, t ≤ 10 sec.
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production
5. EAS Condition : T_j=25°C, V_{DD}=50V, V_G=10V, L=0.5mH, R_g=25Ω

Test Circuit

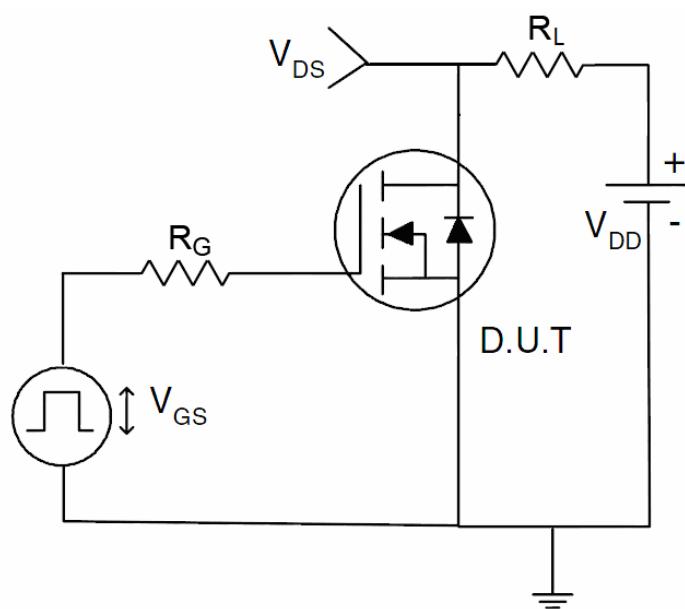
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

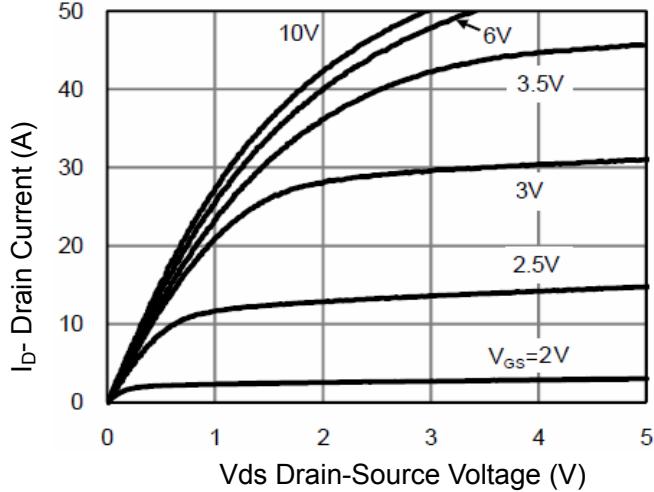


Figure 1 Output Characteristics

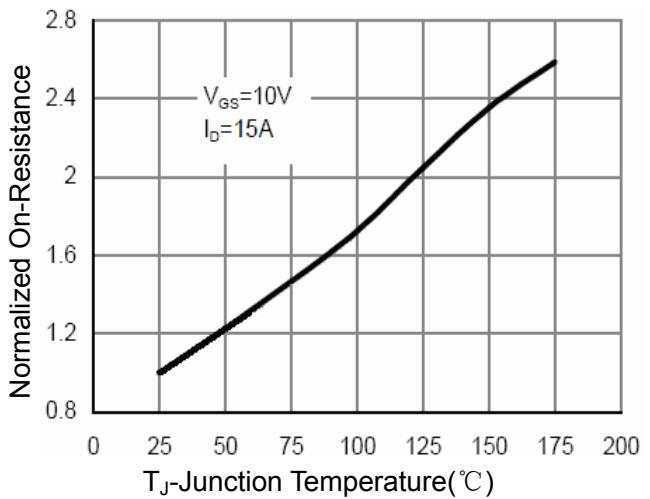


Figure 4 Rdson-JunctionTemperature

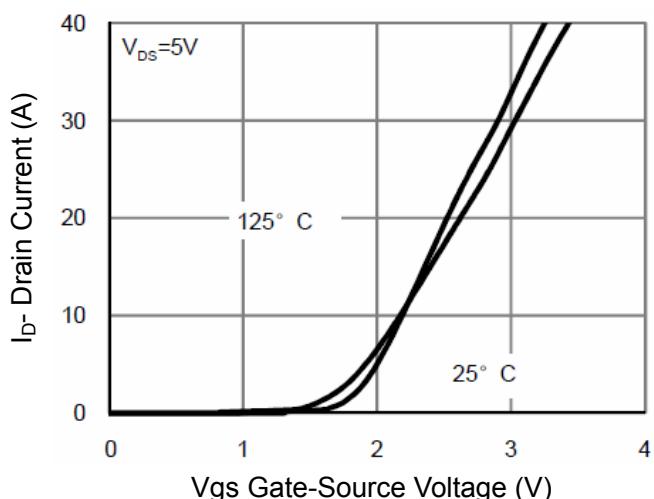


Figure 2 Transfer Characteristics

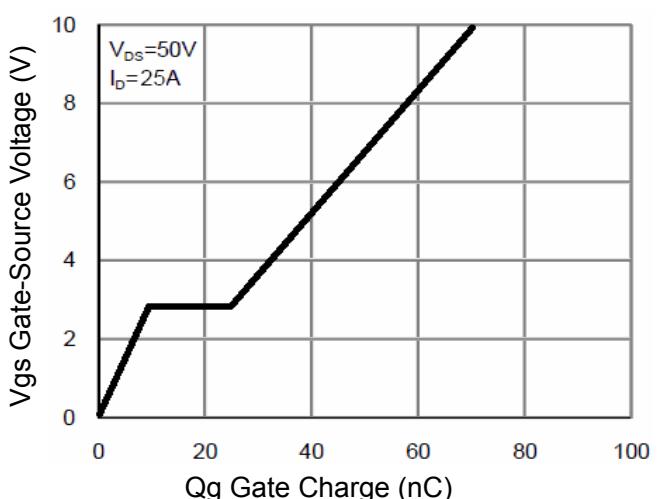


Figure 5 Gate Charge

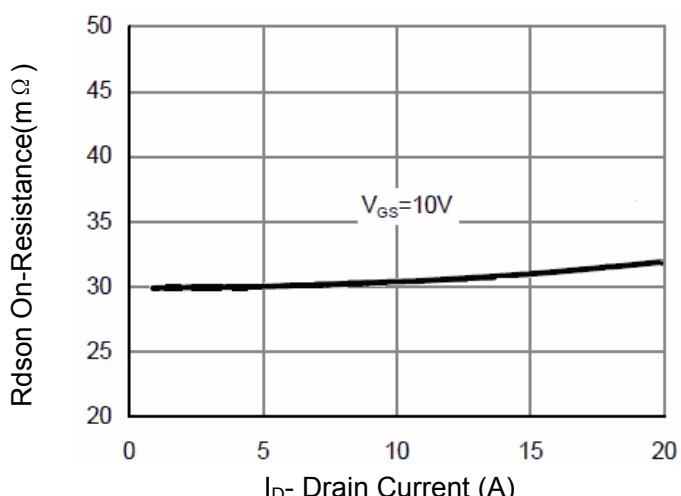


Figure 3 Rdson- Drain Current

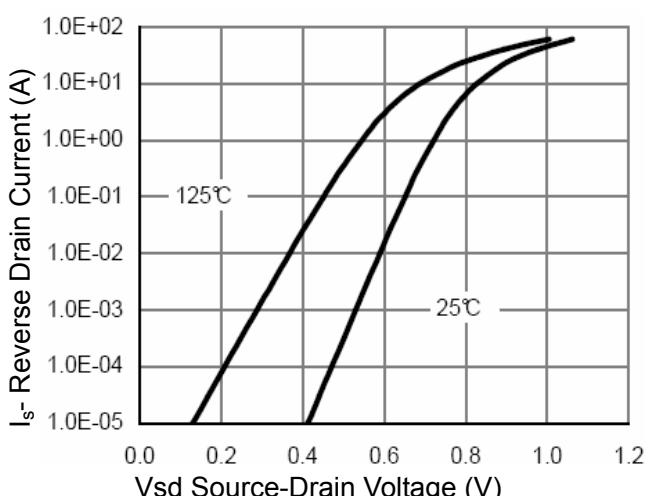


Figure 6 Source- Drain Diode Forward

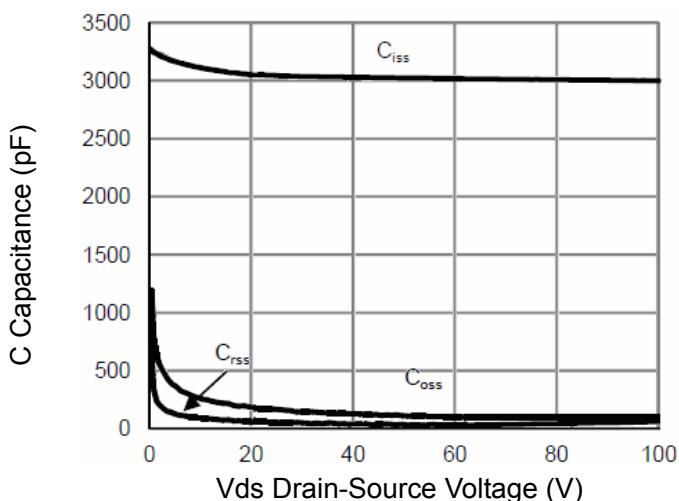


Figure 7 Capacitance vs Vds

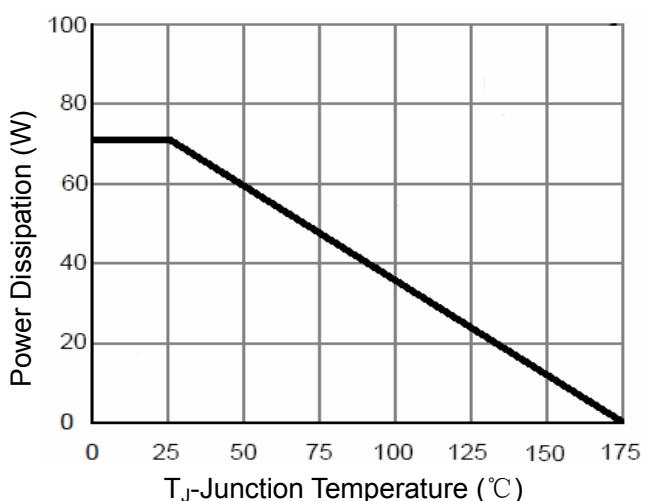


Figure 9 Power De-rating

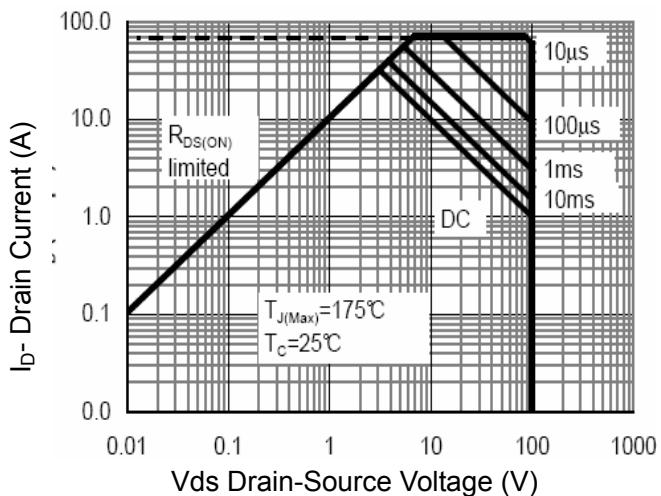


Figure 8 Safe Operation Area

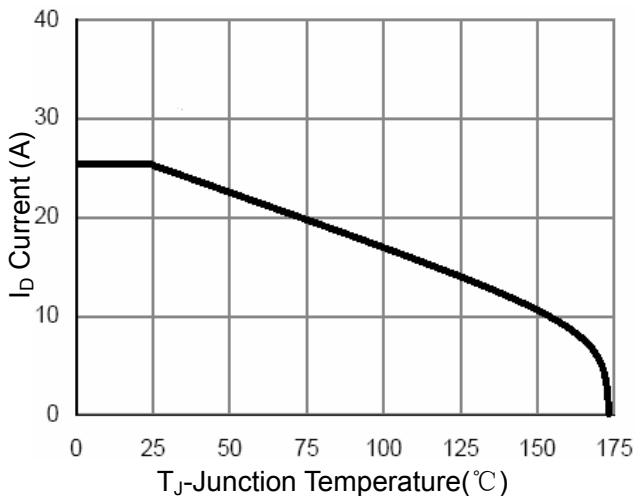


Figure 10 ID Current- Junction Temperature

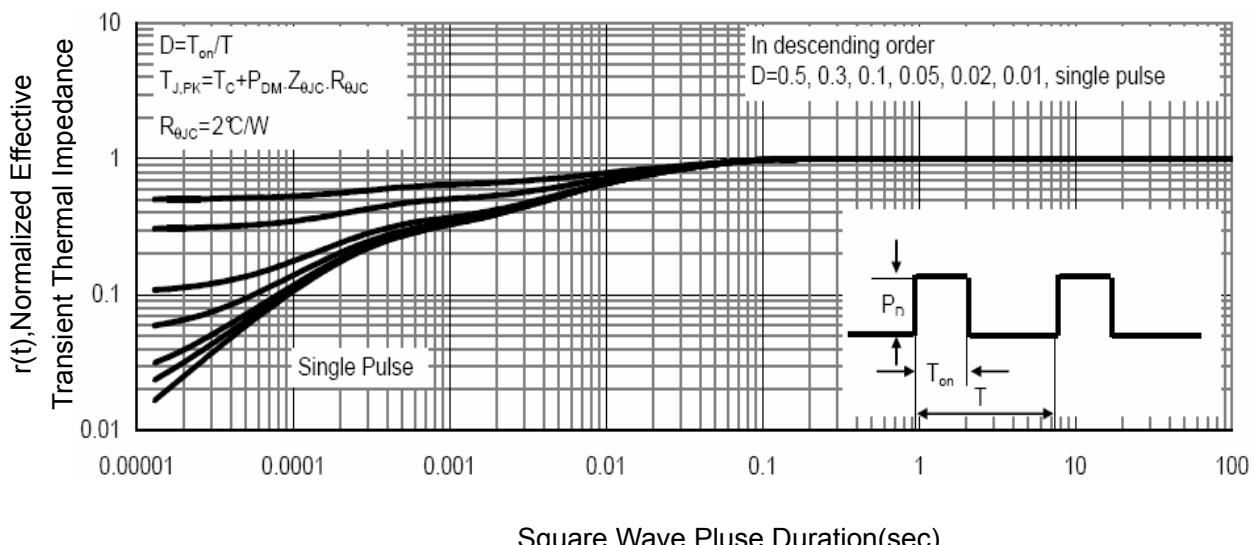
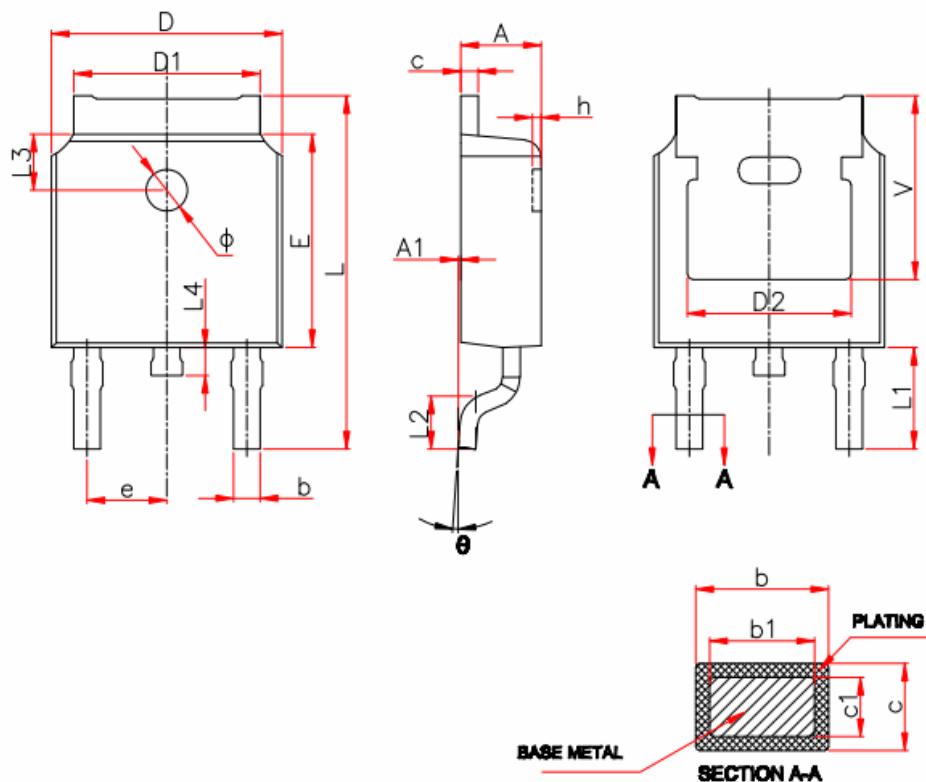


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252 Package Information



Symbol	Millimeters	
	Min.	Max.
A	2.20	2.40
A1	0.00	0.13
b	0.66	0.86
b1	0.73	0.79
c	0.46	0.58
c1	0.50	0.52
D	6.50	6.70
D1	5.10	5.46
D2	4.83 REF.	
E	6.00	6.20
e	2.19	2.39
L	9.80	10.40
L1	2.90 REF.	
L2	1.40	1.70
L3	1.60 REF.	
L4	0.60	1.00
φ	1.10	1.30
θ	0°	8°

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